

ABSTRACT OF THE DISCLOSURE

Purpose: To present a vertical probe card capable of reusing without replacing a broken probe if a probe is broken.

Constitution: A vertical probe card having vertical probes 100, being used in measurement of electric characteristics of an LSI chip 610 to be measured, comprising a main substrate 300 forming conductive patterns 310, a plurality of probes 100 drooping vertically from the main substrate 300, and a probe support 200 provided at the back side of the main substrate 300 for supporting the probes 100, in which the probe support 200 is disposed parallel to the main substrate 300, and has an upper guide plate 210 and a lower guide plate 220 for supporting the probes 100 by passing the through-holes 211, 221 opened in each, and the lower guide plate 220 is composed of three substrates 220A, 220B, 220C laminated separately.

Selected Drawing: Fig. 2.